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Amel  
corresponding interval maintaining means for keeping each rail included in said first rail group at an interval corresponding to an arrangement of locations to be measured on a substrate subjected to measurement,

wherein said plurality of probe units each comprise a probing needle to be brought into contact with a surface of said substrate.

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A2  
7. (Amended) A substrate testing method using a plurality of probe units disposed to cover respective intersections of rails included in a first rail group made of a plurality of rails disposed in parallel with each other and rails included in a second rail group made of a plurality of rails disposed in parallel with each other in a direction that crosses said first rail group, said plurality of probe units being movable along the rails included in said first rail group and said second rail group and each comprising a probing needle to be brought into contact with a surface of a substrate subjected to measurement, wherein said probing needles are brought into contact with said substrate in a state in which an arrangement of said plurality of probe units is concurrently adjusted so that an interval between said probing needles corresponds to an arrangement of locations to be measured on said substrate.

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#### REMARKS

Claims 1-7 are pending. The Examiner rejected claims 1-5 and 7. Claim 6 was objected to as being dependent upon a rejected base claim and would be allowable if rewritten in independent form including all of the limitations of the base claim and any intervening claims. By way of this amendment claims 2 and 7 have been amended. Care has been exercised to avoid the introduction of new matter. Support for the amendment is found at page 3, lines 5-28.

Claims 1-4 and 7 were rejected under 35 U.S.C. § 102(e) as being anticipated by Root (U.S. Pat. No. 6,201,402). Applicants note that Examiner Nguyen informed Applicants during a